

FDS2672

N-Channel UltraFET Trench® MOSFET

200V, 3.9A, 70mΩ

Features

- Max $r_{DS(on)} = 70m\Omega$ at $V_{GS} = 10V$, $I_D = 3.9A$
- Max $r_{DS(on)} = 80 \text{m}\Omega$ at $V_{GS} = 6V$, $I_D = 3.5A$
- Fast switching speed
- High performance trench technology for extremely low r_{DS(on)}
- RoHS compliant

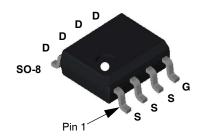


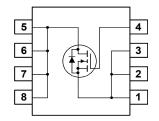
General Description

This single N-Channel MOSFET is produced using Fairchild Semiconductor's advanced UltraFET Trench® process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

Application

■ DC-DC conversion





MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

| Symbol | Parameter | | Ratings | Units |
|-----------------------------------|-----------------------------------|-----------|------------|-------|
| V _{DS} | Drain to Source Voltage | | 200 | V |
| V _{GS} | Gate to Source Voltage | | ±20 | V |
| 1 | Drain Current -Continuous | (Note 1a) | 3.9 | ۸ |
| ID | -Pulsed | | 50 | A |
| E _{AS} | Single Pulse Avalanche Energy | (Note 3) | 37.5 | mJ |
| Power Dissipation | | (Note 1a) | 2.5 | w |
| P_{D} | Power Dissipation | (Note 1b) | 1.0 | VV |
| T _J , T _{STG} | Operating and Storage Temperature | | -55 to 150 | °C |

Thermal Characteristics

| $R_{\theta JC}$ | Thermal Resistance, Junction to Case | (Note 1) | 25 | |
|-----------------|---|-----------|-----|------|
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient | (Note 1a) | 50 | °C/W |
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient | (Note 1b) | 125 | |

Package Marking and Ordering Information

| Device Marking | Device | Reel Size | Tape Width | Quantity |
|----------------|---------|-----------|------------|------------|
| FDS2672 | FDS2672 | 13" | 12mm | 2500 units |

Units

Electrical Characteristics T_J = 25°C unless otherwise noted

Parameter

| Off Characteristics | | | | | | | | |
|--|---|---|-----|-----|------------|----------|--|--|
| BV _{DSS} | Drain to Source Breakdown Voltage | $I_D = 250 \mu A, V_{GS} = 0 V$ | 200 | | | V | | |
| $\frac{\Delta BV_{DSS}}{\Delta T_{J}}$ | Breakdown Voltage Temperature Coefficient | I_D = 250 μ A, referenced to 25°C | | 206 | | mV/°C | | |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{DS} = 160V, V _{GS} =0V | | | 1 | μА | | |
| I _{GSS} | Gate to Source Leakage Current | $V_{DS} = 160V, V_{GS} = 0V$ $T_{J} = 55^{\circ}C$ $V_{GS} = \pm 20V$ | | | 10 ±100 | μA nA | | |

Test Conditions

Min

Тур

Max

On Characteristics (Note 2)

Symbol

| V _{GS(th)} | Gate to Source Threshold Voltage | $V_{GS} = V_{DS}, I_D = 250 \mu A$ | 2 | 2.9 | 4 | V |
|--|---|--|---|-----|-----|-------|
| $\frac{\Delta V_{GS(th)}}{\Delta T_J}$ | Gate to Source Threshold Voltage Temperature Coefficient | I_D = 250 μ A, referenced to 25°C | | -11 | | mV/°C |
| | | $V_{GS} = 10V, I_D = 3.9A$ | | 59 | 70 | |
| r _{DS(on)} | Drain to Source On Resistance | $V_{GS} = 6V, I_D = 3.5A$ | | 63 | 80 | mΩ |
| | | $V_{GS} = 10V$, $I_D = 3.9A$, $T_J = 125$ °C | | 124 | 148 | |
| 9 _{FS} | Forward Transcondductance | $V_{DS} = 10V, I_{D} = 3.9A$ | | 15 | | S |

Dynamic Characteristics

| C _{iss} | Input Capacitance | 1001/1/ | | 1905 | 2535 | pF |
|------------------|------------------------------|---|--|------|------|----|
| C _{oss} | Output Capacitance | V _{DS} = 100V, V _{GS} = 0V, f = 1MHz | | 100 | 135 | pF |
| C _{rss} | Reverse Transfer Capacitance | | | 30 | 45 | pF |
| R_g | Gate Resistance | f = 1MHz | | 0.7 | | Ω |

Switching Characteristics

| t _{d(on)} | Turn-On Delay Time | | 22 | 35 | ns |
|---------------------|-------------------------------|--|----|----|----|
| t _r | Rise Time | $V_{DD} = 100V, I_{D} = 3.9A$ $V_{GS} = 10V, R_{GEN} = 6\Omega$ | 10 | 20 | ns |
| $t_{d(off)}$ | Turn-Off Delay Time | V _{GS} = 10V, R _{GEN} = 012 | 35 | 56 | ns |
| t _f | Fall Time | | 10 | 20 | ns |
| Q _{g(TOT)} | Total Gate Charge at 10V | | 33 | 46 | nC |
| Q _{gs} | Gate to Source Gate Charge | V _{DD} =100V I _D = 3.9A | 11 | | nC |
| Q _{gd} | Gate to Drain "Miller" Charge | | 7 | | nC |

Drain-Source Diode Characteristics

| V_{SD} | Source to Drain Diode Voltage | $V_{GS} = 0V, I_S = 3.9A$ | 0.75 | 1.2 | V |
|-----------------|-------------------------------|--|------|-----|----|
| t _{rr} | Reverse Recovery Time | $I_F = 3.9A$, di/dt = $100A/\mu s$ | 67 | 101 | ns |
| Q _{rr} | Reverse Recovery Charge | I _F = 3.9A, di/dt = 100A/μs | 179 | 269 | nC |

1. R_{θ,JA} is the sum of the junction-to-case and case-to- ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{θ,JC} is guaranteed by design while R_{θ,CA} is determined by the user's board design.



a) 50°C/W (10 sec) 62.5°C/W steady state when mounted on a 1in² pad of 2 oz copper



b) 125°C/W when mounted on a minimum pad .

Scale 1:1 on letter size paper

- 2: Pulse Test: Pulse Width < 300 us, Duty Cycle < 2.0%. 3: Starting $T_J=25^{\circ}C$, L = 3mH, $I_{AS}=5A$, $V_{DD}=100V$, $V_{GS}=10V$

Typical Characteristics T_J = 25°C unless otherwise noted

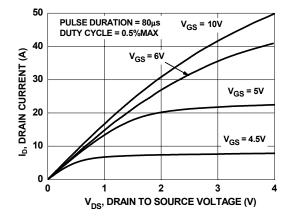


Figure 1. On Region Characteristics

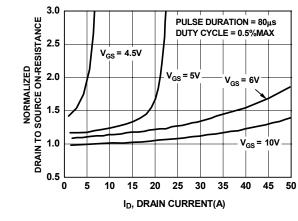


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

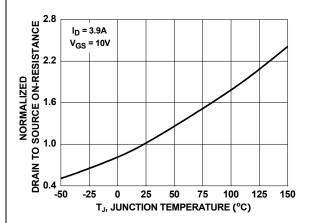


Figure 3. Normalized On Resistance vs Junction Temperature

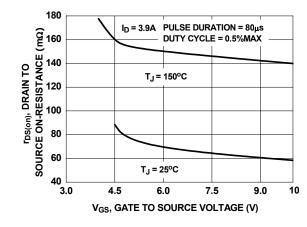


Figure 4. On-Resistance vs Gate to Source Voltage

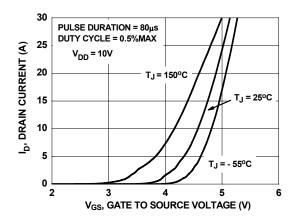


Figure 5. Transfer Characteristics

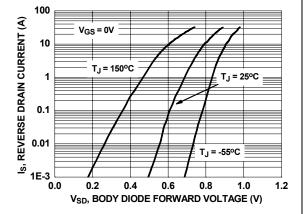
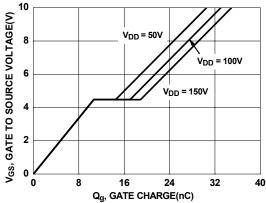


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

100

f = 1MHz VGS = 0V

Typical Characteristics T_J = 25°C unless otherwise noted



40 0.1 1 10 V_{DS}, DRAIN TO SOURCE VOLTAGE (V)

10000

1000

100

10

CAPACITANCE (pF)



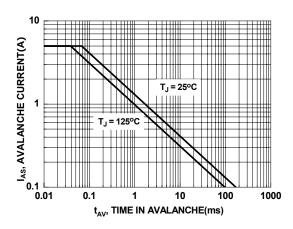


Figure 8. Capacitance vs Drain to Source Voltage

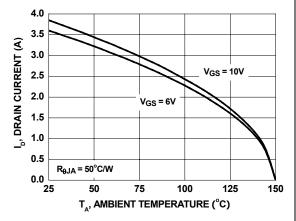


Figure 9. Unclamped Inductive Switching Capability

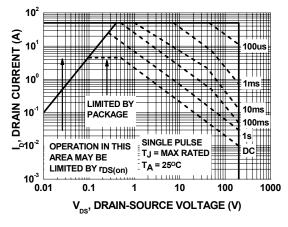


Figure 10. Ambient Continuous Drain Current vs Case Temperature

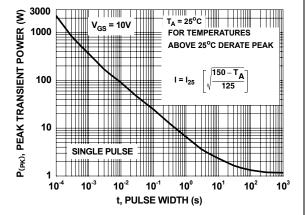


Figure 11. Forward Bias Safe Operating Area

Figure 12. Single Pulse Maximum Power Dissipation



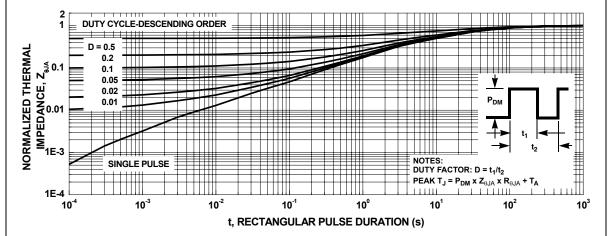


Figure 13. Transient Thermal Response Curve

Thermal characterization performed using the conditions described in Note 1b Transient thermal response will change depending on the circuit board design

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